

Study of alignment procedure for OPERA emulsion brick

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Outline

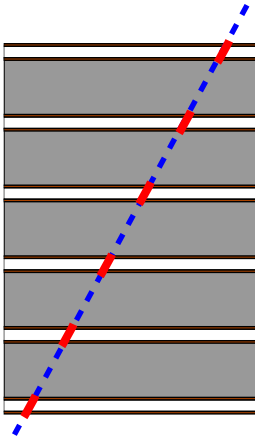
- 1 Introduction
 - OPERA Brick
 - Geometrical defects
 - CR exposition
- 2 Analysis
 - Alignment procedure
 - Offset distributions
 - Exposing conditions
- 3 Conclusions

OPERA Brick

Emulsion Cloud Chamber

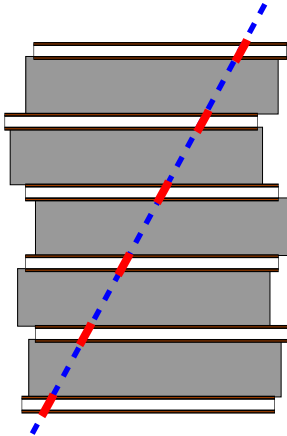
- $(DX) \times (DY) = 128 \times 103 \text{ mm}^2$
- Length $(DZ) = 81 \text{ mm}$
- 56 Pb plates $d = 1 \text{ mm}$
- 57 Emulsion plates
 $d = (44 + 205 + 44) \mu\text{m}$

Geometrical defects



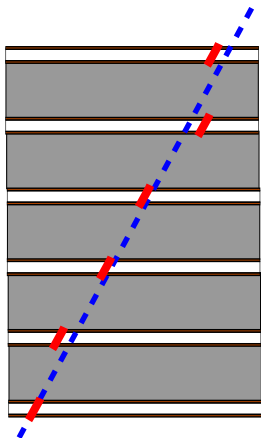
- Plates misalignment

Geometrical defects



- Plates misalignment

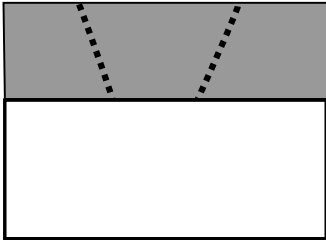
Geometrical defects



- Plates misalignment — 2D affine transforms:

$$\begin{pmatrix} x \\ y \end{pmatrix} = \begin{pmatrix} a_{11} & a_{12} \\ a_{21} & a_{22} \end{pmatrix} \begin{pmatrix} x \\ y \end{pmatrix} + \begin{pmatrix} b_1 \\ b_2 \end{pmatrix}$$

Geometrical defects

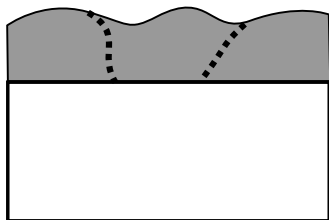


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- Emulsion distorsion

Geometrical defects

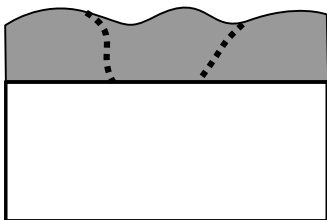


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- Emulsion distorsion — Shifts for each point $f(\cdot)$

Geometrical defects



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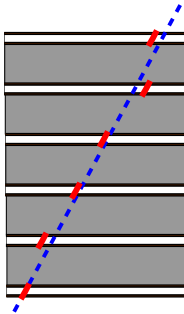
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Solutions:

- X-ray marks (for example, Japan)

Geometrical defects



- Plates misalignment — 2D affine transforms:

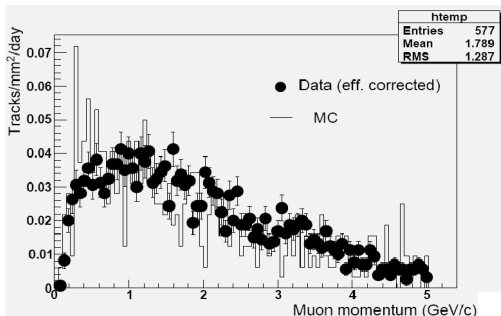
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- Emulsion distortion — Shifts for each point $f(\cdot)$

Solutions:

- X-ray marks (for example, Japan)
- CR exposure (Gran Sasso)

Cosmic Rays at Gran Sasso



CR exposure

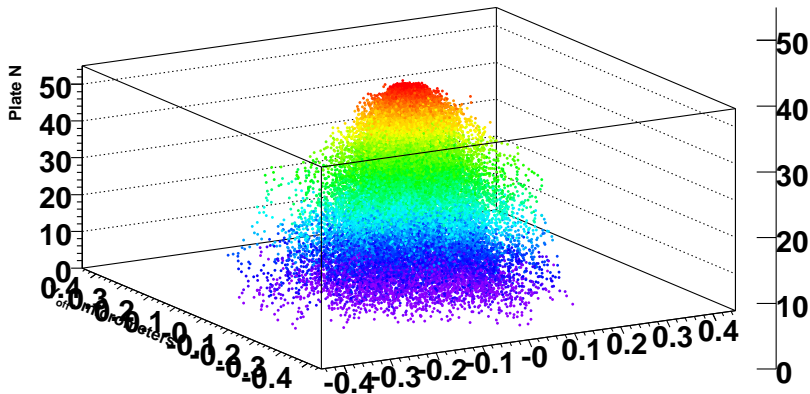
- flux is about $2 \text{ tracks/mm}^2 / 400 \text{ mrad}$ per day of exposure
- about 70% with $E > 1 \text{ GeV}$
- about < 10% are e^- (the rest are all μ^-)

Analysys scheme

- Simulation of CR μ^- tracks in unshifted ECC brick — FedraVMC
- Alignment procedure (shifts only) — FEDRA
- Results of alignment $\{X_{off}, Y_{off}\} \Rightarrow \{\sigma_x, \sigma_y\}$
- Obtain dependences: $\sigma = \sigma(N_{tracks}, E_\mu, \theta_{max})$

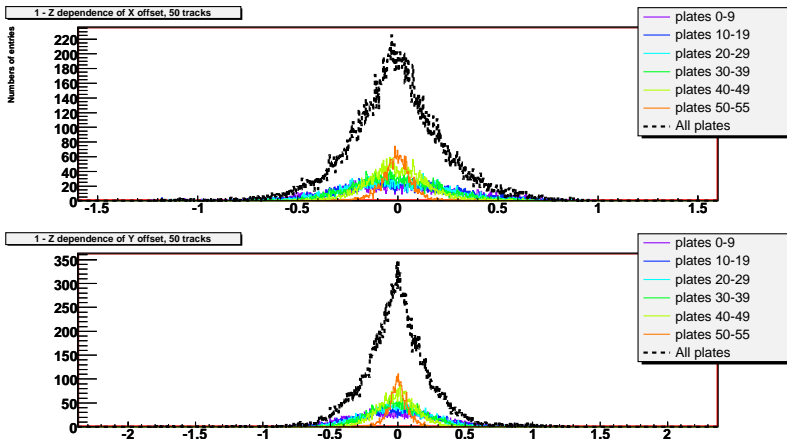
X_{Off} and Y_{Off} distributions

1) Offset for 500 tracks



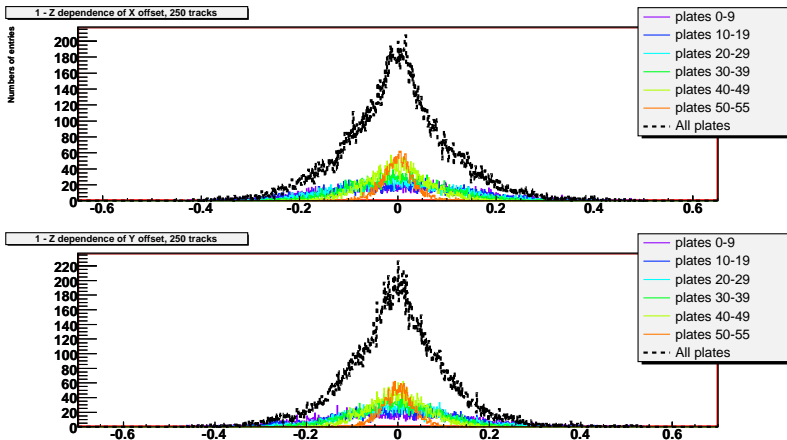
X_{off} and Y_{off} distributions

50 tracks



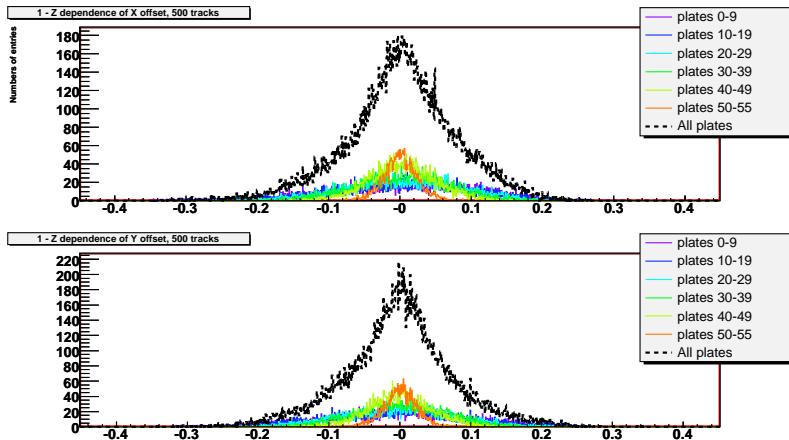
X_{off} and Y_{off} distributions

250 tracks



X_{off} and Y_{off} distributions

500 tracks



Exposure duration

N_{tracks}	20	30	50	100	500
$\delta\theta$	31%	19%	11%	6%	2%
$\sigma, \mu\text{m}$	0.7	0.61	0.46	0.33	0.15

- Alignment accuracy improves tracking quality
— need **more** exposure!

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- Cosmic background makes reconstruction more difficult
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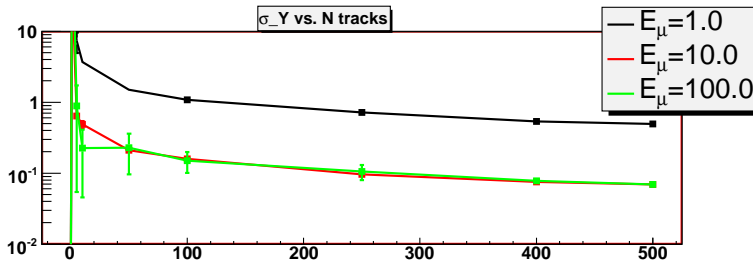
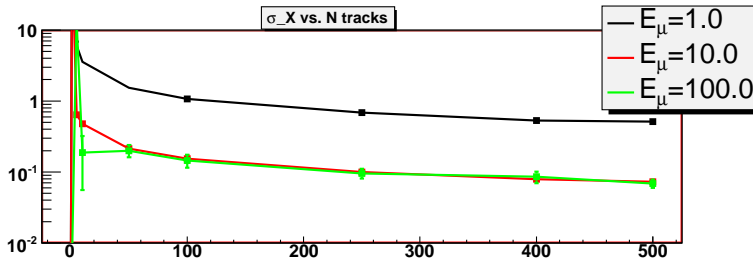
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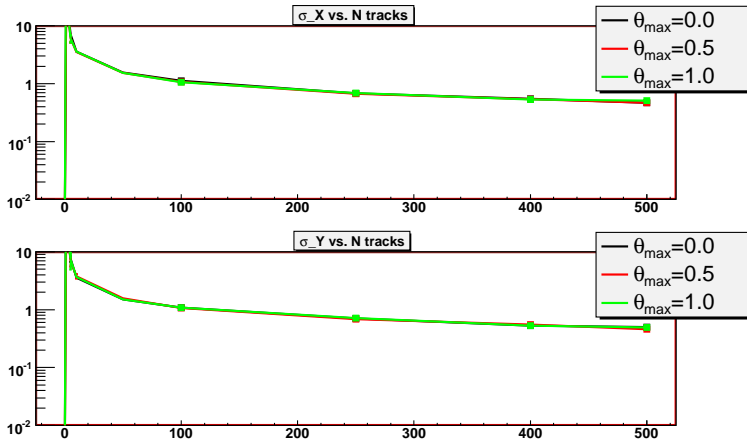


Need analysis of $\varepsilon_{tr}(N_{tracks})$

Exposing conditions



Exposing conditions



Conclusions

- MC analysis of full brick alignment shows to be useful.
- Resolution of alignment procedure had been calculated.
- There is room for alignment procedure improvements
- Full spectrum of CR μ^- to be simulated
- Tracking quality dependence on N_μ needs to be analysed — to determine optimal T_{exp}